


<b>Search Notes</b> 	<b>Application/Control No.</b> 10058732	<b>Applicant(s)/Patent Under Reexamination</b> IMAI ET AL.
	<b>Examiner</b> LENA NAJARIAN	<b>Art Unit</b> 3686

SEARCHED			
Class	Subclass	Date	Examiner
705	2, 3	3/19/08	LN
705	2, 3	3/20/08	LN
707	104.1	2/3/09	LN
(Updated all	of the above)	6/18/09	LN

SEARCH NOTES		
Search Notes	Date	Examiner
East (see attached printout) USPAT;US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	3/18/08	LN
East (see attached printout) USPAT;US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	3/19/08	LN
East (see attached printout) USPAT;US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	3/20/08	LN
East (see attached printout) USPAT;US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	7/28/08	LN
EIC 705 template reviewed and considered	6/17/09	LN
Forward/backward search on previously applied prior art	6/18/09	LN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
705	2 and 3	6/18/09	LN
707	104.1	6/18/09	LN
	PGPUB text search (see interference search printout)	6/18/09	LN

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